



CE-EMC TEST REPORT

Prepared for :

**MMD (Shanghai) Electronics Technology Co., Ltd.
Room 5060A, No.2 Building, 555 Dong Chuan Road, Min Hang District,
Shanghai, 200241, China**

Product: Wired game headset

Trade Name: AOC

Model Name: GH300, GH200, GH210

Date of Test: Dec. 28, 2020 – Jan. 04, 2021

Date of Report: Jan. 04, 2021

Report Number: HK2012304045-1ER

Prepared By :

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TEST REPORT VERIFICATION

Applicant : MMD (Shanghai) Electronics Technology Co., Ltd.
 Address : Room 5060A, No.2 Building, 555 Dong Chuan Road, Min Hang District, Shanghai, 200241, China
 Manufacturer : Dongguan Desheng Industrial Co., Ltd.
 Address : Area A5, Shichong Industrial Park, Shipai Town, Dongguan City, China
 EUT Description : Wired game headset
 (A) Model No. : GH300
 (B) Serial Model : GH200, GH210
 (C) Power Supply : DC5V

Standards..... EN 55032:2015
 EN 55035:2017


This device described above has been tested by HUAKE, and the test results show that the equipment under test (EUT) is in compliance with the 2014/30/EU requirements. And it is applicable only to the tested sample identified in the report.

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Test Result..... **Pass**

Date of Test: Dec. 28, 2020 - Jan. 04, 2021

Prepared by: 
 Project Engineer

Reviewed by: 
 Project Supervisor

Approved by: 
 Technical Director



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**** Modified History ****

Revision	Description	Issued Data	Remark
Revision 1.0	Initial Test Report Release	2021/01/04	Jason Zhou



1. TEST SUMMARY

Test procedures according to the technical standards:

EMC Emission				
Standard	Test Item	Limit	Judgment	Remark
EN 55032	Conducted Emission	Class B	N/A	
	Radiated Emission	Class B	PASS	
EN 61000-3-2	Harmonic Current Emission	Class A or D NOTE (2)	N/A	
EN 61000-3-3	Voltage Fluctuations & Flicker	-----	N/A	
EMC Immunity				
Section EN 55035	Test Item	Performance Criteria	Judgment	Remark
EN 61000-4-2	Electrostatic Discharge	B	PASS	
EN 61000-4-3	RF electromagnetic field	A	PASS	
EN 61000-4-4	Fast transients	B	N/A	
EN 61000-4-5	Surges	B	N/A	
EN 61000-4-6	Injected Current	A	N/A	
EN 61000-4-8	Power Frequency Magnetic Field	A	N/A	
EN 61000-4-11	Volt. Interruptions Volt. Dips	B / C / C NOTE (3)	N/A	

NOTE:

- (1) "N/A" denotes test is not applicable in this Test Report
- (2) The power consumption of EUT is less than 75W and no Limits apply.
- (3) Voltage dip: 100% reduction – Performance Criteria **B**
Voltage dip: 30% reduction – Performance Criteria **C**
Voltage Interruption: 100% Interruption – Performance Criteria **C**
- (4) For client's request and manual description, the test will not be executed.



1.1 TEST FACILITY

Shenzhen HUAKE Testing Technology Co., Ltd.
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1.2 MEASUREMENT UNCERTAINTY

The reported uncertainty of measurement $y \pm U$, where expanded uncertainty U is based on a standard uncertainty multiplied by a coverage factor of $k=2$, providing a level of confidence of approximately 95%.

A. Conducted Measurement :

Measurement Frequency Range	Uncertainty	NOTE
150 KHz ~ 30MHz	±2.71dB	

B. Radiated Measurement :

Measurement Frequency Range	Uncertainty	NOTE
30MHz ~ 1000MHz	±3.90dB	
1GHz ~6GHz	±4.28dB	